

L20	232	quantiz\$6 with output with voltage with (variab\$5 differen\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:58
L21	318	sampl\$5 with clock with ((transition fall rise) near2 time)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:53
L22	1	20 and 21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:53
L23	336	sampl\$5 with clock with ((transit\$6 fall rise) near2 time)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:57
L24	1	20 and 23	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:53
L25	1911445	(measur\$5 test\$5).ti,ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:54
L26	15799	25 and ((transit\$6 fall rise) near2 time)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:15
L27	3	20 and 26	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:55
L28	504	sampl\$5 with clock with ((transit\$8 fall\$6 rise rising) near2 time)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:31
L29	73	25 and 28	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:58

L30	1125	quantiz\$6 with output with voltage	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:00
L31	2	29 and 30	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 11:59
L32	3	29 and (quantiz\$6 with output)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:02
L33	4	28 and 30	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:04
L34	68	(reference near2 voltage) same quantiz\$6 same clock same sampl\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:00
L35	5	25 and 34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:11
L36	114381	(test\$6 near3 (chip IC circuit))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:57
L37	4	34 and 36	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:13
L38	16	("3678505" "3790886" "4251754" "4390864" "4455613" "4495586" "4555765" "4647862").PN. OR ("4906916").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/22 12:25
L39	0	38 and 34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:25

L40	4	28 and 34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:26
L41	3	(variable near3 reference near2 voltage) same quantiz\$6 same clock same sampl\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:30
L42	25	sampl\$5 with clock with (((transit\$8 fall\$6 rise rising) near2 time) with (quarter half)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:44
L43	5	36 and 42	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:42
L44	160108	(test\$6 near9 (chip IC circuit))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:42
L45	5	42 and 44	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:43
L46	3	sampl\$5 with clock with (((transit\$8 fall\$6 rise rising) near2 time) with (quarter)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:44
L47	33564	(test\$6 near3 (chip IC circuit)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:57
L48	8052	(test\$6 near3 (chip IC)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:59
L49	3	48 and "455"/\$8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 12:57

L50	16883	(test\$6 near3 (chip IC)).ti,ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:01
L51	2386	quantiz\$6 same clock same sampl\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:00
L52	0	50 and 51	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:00
L53	23828	(test\$6 near9 (chip IC)).ti,ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:02
L54	2	51 and 53	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:01
L55	51928	(test\$6 near9 (chip IC))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:03
L56	2	55 and 34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:03
L57	50	55 and 51	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:03
L58	8464	(measur\$6 test\$6) near6 ((transit\$6 fall rise) near2 time)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:16
L59	93	53 and 58	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/22 13:17